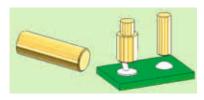


## **Special Versions**

		-				0
(17)H	(17)T	С	SP	PT	IK	IP
H = Synthetic Head with Ring	T = Insulated BeCu Head	C = High Current (Groove Mark)	SP = Step Probe	PT = Position Test	IK = Insulating Cap	IP = Insulated Pin



## **Typical Tip Styles and Applications**



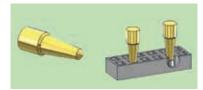
**Flat** Suitable for solder pads and contact pins.



**Spherical** For testing clean contact surfaces, does not leave marks or scratches.



Conical Universal tip style with different angles of 10°, 15°, 30°, 60°, 90° or 120° for contacting solder



**Multipoint connectors**This probe tip was designed for contacting multipoint connectors.



**4-Point Crown** 

pads and holes.

For pad surfaces and soldered pins. The sharp edges penetrate flux residues and oxide layers.



Crown

For wire wrap posts, even if the contacts are bent or twisted.



Star

For testing plated through holes and pads. The sharp edges penetrate contamination and oxide layers.



Serrated

Universal tip style for wires, contact pins and wire wrap posts, even for bent component leads.



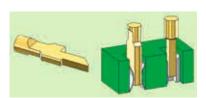
Concave

For a smooth contact of pins and wire wrap posts. The risk of contamination can be minimized by using a self cleaning version of this tip style.



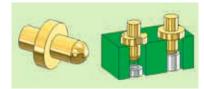
Tulip

Used for severe contacting of plated of filled through holes.



Spade

For twist proof contacting of connector elements.



Step Probes

For position and presence tests of connectors.



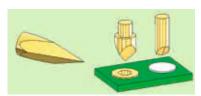
**Insulating Cap** 

For detecting the correct length and straightness of pins.



Insulating Cap, slotted

For detecting the correct length and straightness of flat pins.



Multi-sided

For via holes and solder pads. The sharp edges penetrate flux residues and oxide layers.



Rolling ball

For side contacts with lateral movements of the test item. The contact element is a rolling ball.